Se	arch Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/750,175	DANG ET AL.
Examiner	Art Unit
John P. Trimminas	2138

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Class	Subclass	Date	Examiner
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INI	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	1		

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
NPL Search: pld fpga configure scan chain register.	9/12/2006	JPT
Dble Patent Search: Negative.	9/12/2006	JPT
Class Search: 326/41,38, 714/724, 726,734,731,30. Text strategy attached.	9/12/2006	JPT